



Contribution ID: 148

Type: Poster

LPA-UHI100 platform : an optimised laser-driven electron sources for device testing

An overview of the LPA-UHI100 platform will be detailed, including service improvement that allows increasing the repetition rate of the laser-driven electron source.

A detailed plan of the implementation and tests of new ML toolkit developed by GSI (GeOFF) will be presented as well. This should reduce the optimisation time for delivering optimised electron beam to users.

Work-package

Facility identifier

LPA-UHI100

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Session Classification: Cocktail - Poster session